# **IGBT - Field Stop, Trench**

650 V, 60 A

## FGH60T65SHD

### Description

Using novel field stop IGBT technology, ON Semiconductor's new series of field stop 3<sup>rd</sup> generation IGBTs offer the optimum performance for solar inverter, UPS, welder, telecom, ESS and PFC applications where low conduction and switching losses are essential.

#### **Features**

- Maximum Junction Temperature:  $T_J = 175$ °C
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage:  $V_{CE(sat)} = 1.6 \text{ V (Typ.)} @ I_C = 60 \text{ A}$
- 100% of the Parts Tested for I<sub>LM</sub> (Note 1)
- High Input Impedance
- Fast Switching
- Tighten Parameter Distribution
- This Device is Pb-Free and is RoHS Compliant

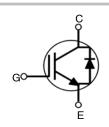
### **Applications**

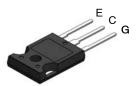
• Solar Inverter, UPS, Welder, Telecom, ESS, PFC



### ON Semiconductor®

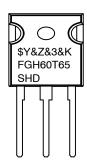
www.onsemi.com





TO-247-3LD CASE 340CH

### **MARKING DIAGRAM**



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code

&3 = Numeric Date Code

&K = Lot Code

FGH60T65SHD = Specific Device Code

### **ORDERING INFORMATION**

See detailed ordering and shipping information in the package dimensions section on page 2 of this data sheet.

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### **ABSOLUTE MAXIMUM RATINGS**

Description		Symbol	FGH60T65SHD-F155	Unit
Collector to Emitter Voltage		V <sub>CES</sub>	650	V
Gate to Emitter Voltage		$V_{GES}$	±20	V
Transient Gate to Emitter Voltage			±30	V
Collector Current	T <sub>C</sub> = 25°C	I <sub>C</sub>	120	Α
Collector Current	T <sub>C</sub> = 100°C		60	Α
Pulsed Collector Current (Note 1)	T <sub>C</sub> = 25°C	I <sub>LM</sub>	180	Α
Pulsed Collector Current (Note 2)		I <sub>CM</sub>	180	Α
Diode Forward Current	T <sub>C</sub> = 25°C	I <sub>F</sub>	60	Α
Diode Forward Current	T <sub>C</sub> = 100°C		30	Α
Pulsed Diode Maximum Forward Current (	Note 2)	I <sub>FM</sub>	180	Α
Maximum Power Dissipation	T <sub>C</sub> = 25°C	$P_{D}$	349	W
Maximum Power Dissipation	T <sub>C</sub> = 100°C		174	W
Operating Junction Temperature		TJ	-55 to +175	°C
Storage Temperature Range		T <sub>stg</sub>	-55 to +175	°C
Maximum Lead Temp. for Soldering Purpo	ses, 1/8" from Case for 5 Seconds	T <sub>L</sub>	300	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1.  $V_{CC} = 400 \text{ V}$ ,  $V_{GE} = 15 \text{ V}$ ,  $I_{C} = 180 \text{ A}$ ,  $R_{G} = 27 \Omega$ , Inductive Load

2. Repetitive Rating: Pulse width limited by max. junction temperature.

### THERMAL CHARACTERISTICS

Parameter	Symbol	FGH60T65SHD-F155	Unit
Thermal Resistance, Junction to Case, Max. (IGBT)	$R_{ heta JC}$	0.43	°C/W
Thermal Resistance, Junction to Case, Max. (Diode)	$R_{ heta JC}$	1.25	°C/W
Thermal Resistance, Junction to Ambient, Max.	$R_{ heta JA}$	40	°C/W

### PACKAGE MARKING AND ORDERING INFORMATION

Device	Device Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
FGH60T65SHD-F155	FGH60T65SHD	TO-247-3LD	Tube	ı	ı	30

### ELECTRICAL CHARACTERISTICS OF THE IGBT (T<sub>C</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
OFF CHARACTERISTICS			•	•	-	
Collector to Emitter Breakdown Voltage	BV <sub>CES</sub>	V <sub>GE</sub> = 0 V, I <sub>C</sub> = 1 mA	650	_	_	V
Temperature Coefficient of Breakdown Voltage	$\Delta BV_{CES} / \Delta T_{J}$	I <sub>C</sub> = 1 mA, Referenced to 25°C		0.6		V/°C
Collector Cut-Off Current	I <sub>CES</sub>	V <sub>CE</sub> = V <sub>CES</sub> , V <sub>GE</sub> = 0 V	_	-	250	μΑ
G-E Leakage Current	I <sub>GES</sub>	V <sub>GE</sub> = V <sub>GES</sub> , V <sub>CE</sub> = 0 V	_	_	±400	nA
ON CHARACTERISTICS						
G-E Threshold Voltage	V <sub>GE(th)</sub>	$I_C$ = 60 mA, $V_{CE}$ = $V_{GE}$	4.0	5.5	7.5	V
Collector to Emitter Saturation Voltage	V <sub>CE(sat)</sub>	I <sub>C</sub> = 60 A, V <sub>GE</sub> = 15 V	_	1.6	2.1	V
		I <sub>C</sub> = 60 A, V <sub>GE</sub> = 15 V, T <sub>C</sub> = 175°C	_	2.14	-	V

### ELECTRICAL CHARACTERISTICS OF THE IGBT (T<sub>C</sub> = 25°C unless otherwise noted) (continued)

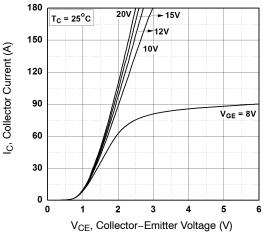
Parameter	Symbol	Test Conditions	Min	Тур	Max	Unit
DYNAMIC CHARACTERISTICS						
Input Capacitance	C <sub>ies</sub>	$V_{CE} = 30 \text{ V}, V_{GE} = 0 \text{ V}, f = 1 \text{ MHz}$	-	2980	_	pF
Output Capacitance	C <sub>oes</sub>		-	110	-	pF
Reverse Transfer Capacitance	C <sub>res</sub>		-	36	_	pF
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{CC} = 400 \text{ V}, I_{C} = 60 \text{ A},$	-	26	_	ns
Rise Time	t <sub>r</sub>	$R_G = 6 \Omega$ , $V_{GE} = 15 V$ , Inductive Load, $T_C = 25^{\circ}C$	_	48	_	ns
Turn-Off Delay Time	t <sub>d(off)</sub>		-	87	-	ns
Fall Time	t <sub>f</sub>		-	47	-	ns
Turn-On Switching Loss	E <sub>on</sub>		-	1.69	-	mJ
Turn-Off Switching Loss	E <sub>off</sub>		-	0.63	-	mJ
Total Switching Loss	E <sub>ts</sub>		-	2.32	_	mJ
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{CC} = 400 \text{ V, } I_{C} = 60 \text{ A,}$ $R_{G} = 6 \Omega, V_{GE} = 15 \text{ V,}$ Inductive Load, $T_{C} = 175^{\circ}\text{C}$	-	25	-	ns
Rise Time	t <sub>r</sub>		-	60	_	ns
Turn-Off Delay Time	t <sub>d(off)</sub>		-	93	_	ns
Fall Time	t <sub>f</sub>		-	72	_	ns
Turn-On Switching Loss	E <sub>on</sub>		-	2.54	_	mJ
Turn-Off Switching Loss	E <sub>off</sub>		-	1.04	_	mJ
Total Switching Loss	E <sub>ts</sub>		-	3.58	_	mJ
Total Gate Charge	Qg	V <sub>CC</sub> = 400 V, I <sub>C</sub> = 60 A,	<u> </u>	102	-	nC
Gate to Emitter Charge	Q <sub>ge</sub>	V <sub>GE</sub> = 15 V	-	18.4	-	nC
Gate to Collector Charge	Q <sub>gc</sub>	1	-	37.5	-	nC

### **ELECTRICAL CHARACTERISTICS OF THE DIODE** ( $T_C = 25$ °C unless otherwise noted)

Parameter	Symbol	Test Condit	ions	Min	Тур	Max	Unit
Diode Forward Voltage	V <sub>FM</sub>	I <sub>F</sub> = 30 A	T <sub>C</sub> = 25°C	-	2.3	2.7	V
			T <sub>C</sub> = 175°C	-	1.9	-	
Reverse Recovery Energy	E <sub>rec</sub>	I <sub>F</sub> = 30 A,	T <sub>C</sub> = 175°C	-	50	-	μJ
Diode Reverse Recovery Time	t <sub>rr</sub>	dI <sub>F</sub> /dt = 200 A/μs	T <sub>C</sub> = 25°C	-	34.6	-	ns
			T <sub>C</sub> = 175°C	-	197	-	
Diode Reverse Recovery Charge	Q <sub>rr</sub>	7	T <sub>C</sub> = 25°C	_	58.6	-	nC
			T <sub>C</sub> = 175°C	-	810	-	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

### TYPICAL PERFORMANCE CHARACTERISTICS



**Figure 1. Typical Output Characteristics** 

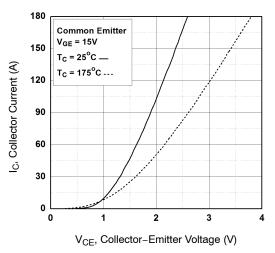


Figure 3. Typical Saturation Voltage Characteristics

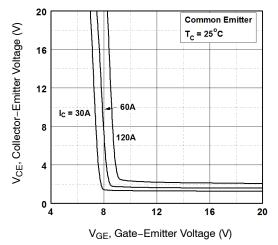


Figure 5. Saturation Voltage vs V<sub>GE</sub>

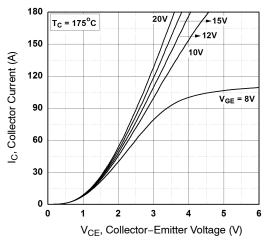


Figure 2. Typical Output Characteristics

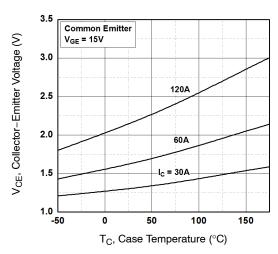


Figure 4. Saturation Voltage vs. Case Temperature at Variant Current Level

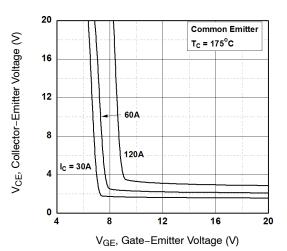


Figure 6. Saturation Voltage vs V<sub>GE</sub>

### TYPICAL PERFORMANCE CHARACTERISTICS (continued)

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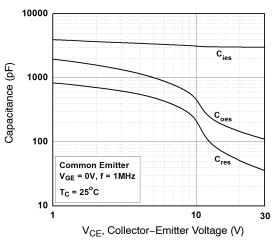
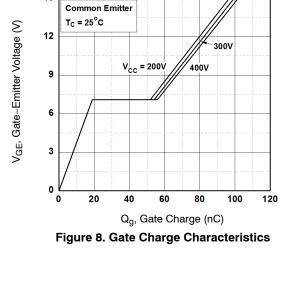


Figure 7. Capacitance Characteristics



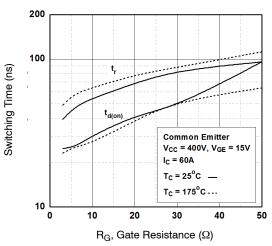


Figure 9. Turn-On Characteristics vs. Gate Resistance

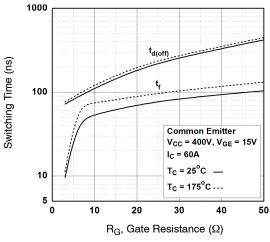


Figure 10. Turn-Off Characteristics vs. Gate Resistance

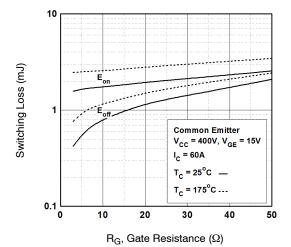


Figure 11. Switching Loss vs. Gate Resistance

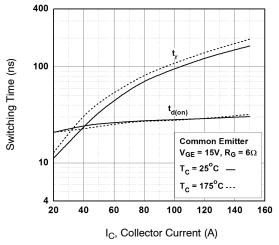


Figure 12. Turn-On Characteristics vs. Collector Current

### TYPICAL PERFORMANCE CHARACTERISTICS (continued)

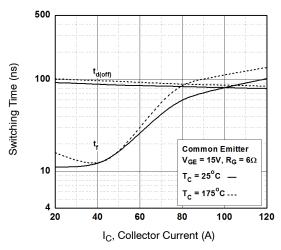


Figure 13. Turn-Off Characteristics vs. Collector Current

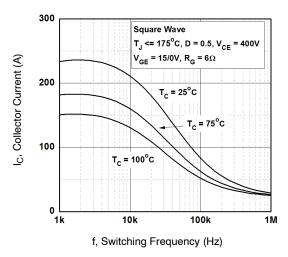


Figure 15. Load Current vs. Frequency

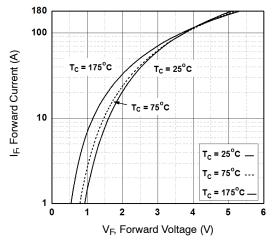


Figure 17. Forward Characteristics

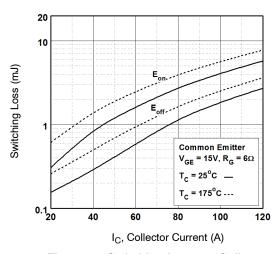


Figure 14. Switching Loss vs. Collector Current

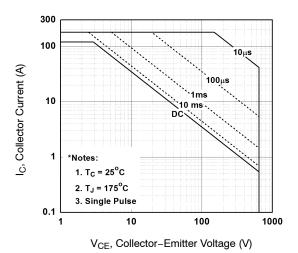


Figure 16. SOA Characteristics

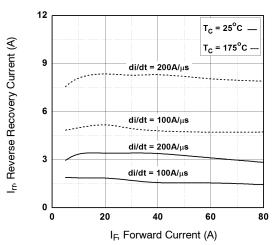


Figure 18. Reverse Recovery Current

### TYPICAL PERFORMANCE CHARACTERISTICS (continued)

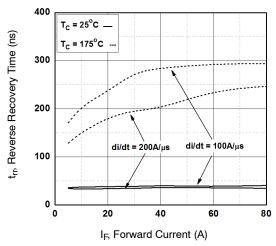


Figure 19. Reverse Recovery Time

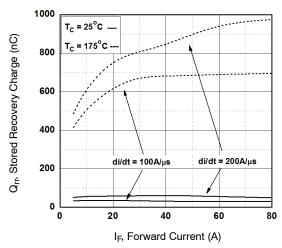


Figure 20. Stored Charge

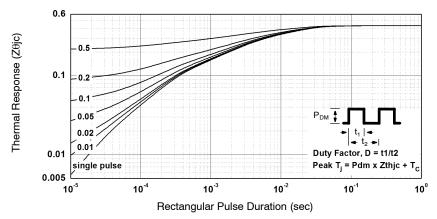


Figure 21. Transient Thermal Impedance of IGBT

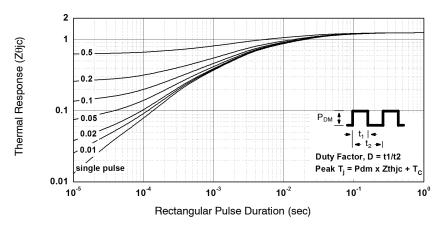
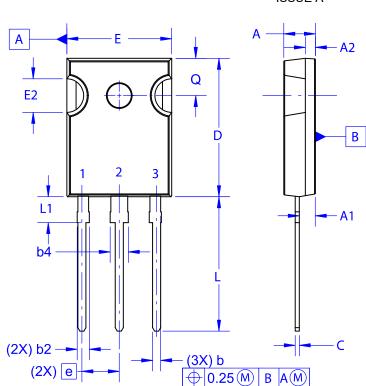


Figure 22. Transient Thermal Impedance of Diode

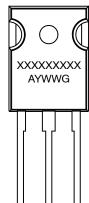
### TO-247-3LD CASE 340CH **ISSUE A**





- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- B. ALL DIMENSIONS ARE IN MILLIMETERS.
- C. DRAWING CONFORMS TO ASME Y14.5 2009.
  D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.

### GENERIC **MARKING DIAGRAM\***



XXXX = Specific Device Code

= Assembly Location

WW = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

	DATE 09 OCT 2019				
ØP —		,		Ø P1 D2	
S E1 —				D1	
21		2			
,				9	

DIM	MILLIMETERS				
DIM	MIN	NOM	MAX		
Α	4.58	4.70	4.82		
<b>A</b> 1	2.29	2.475	2.66		
A2	1.40	1.50	1.60		
D	20.32	20.57	20.82		
Е	15.37	15.62	15.87		
E2	4.96	5.08	5.20		
е	~	5.56	~		
L	19.75	20.00	20.25		
L1	3.69	3.81	3.93		
ØΡ	3.51	3.58	3.65		
Q	5.34	5.46	5.58		
S	5.34	5.46	5.58		
b	1.17	1.26	1.35		
b2	1.53	1.65	1.77		
b4	2.42	2.54	2.66		
С	0.51	0.61	0.71		
D1	13.08	~	~		
D2	0.51	0.93	1.35		
E1	12.81	~	~		
ØP1	6.61	6.73	6.85		

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